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7	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/757,399	YEH ET AL.	
T	Examiner	Art Unit	
╚	TUYEN T. NGUYEN	2832	

SEARCHED					
Class	Subclass	Date	Examiner		
336	65, 90-96, 107, 192, 198	3/31/2005	TTN		
123	634-635	3/31/2005	TTN		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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